

Quantitative Electron Microprobe Analysis

Wavelength Dispersive X-ray Spectrometry (WDS)

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Goal: Measurement of
concentration of all elements
in a microscopic volume

EPMA Analytical procedure

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- Sample preparation (mounting, polishing, carbon coating)
Carbon coating non-conducting material
- Setting up the Electron Microprobe
Voltage, beam conditions, spectrometers, etc.
- Qualitative analysis with EDS and WDS
If nothing is known about the chemical composition
- Measurement of X-ray intensities in standards (**calibration**)
A different standard can be used for each element
- Measurement of X-ray intensities in the specimen and matrix corrections
ZAF corrections

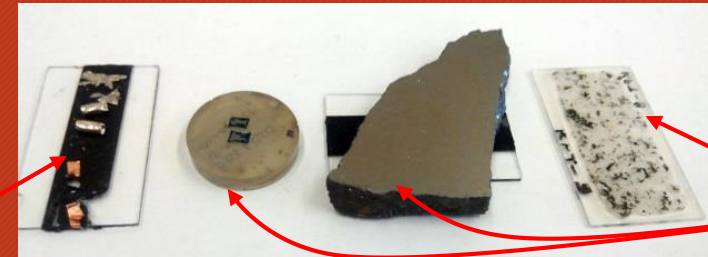
Sample preparation

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- Sample **cut and mounted** in epoxy, if necessary
- **Coarse polished** with 240-600 SiC paper (53-16 μm)
- **Fine polished** with alumina slurry or diamond paste on cloth (grit size 1.00-0.25 μm)
- **Washed** with water in ultrasonic cleaner after each polishing step, **dried** after final step, **wiped** with ethanol

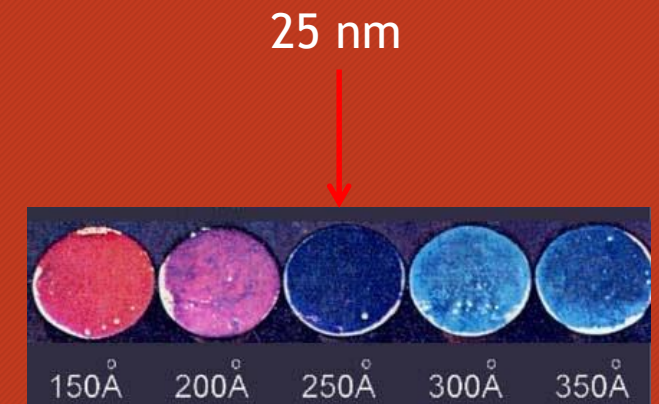
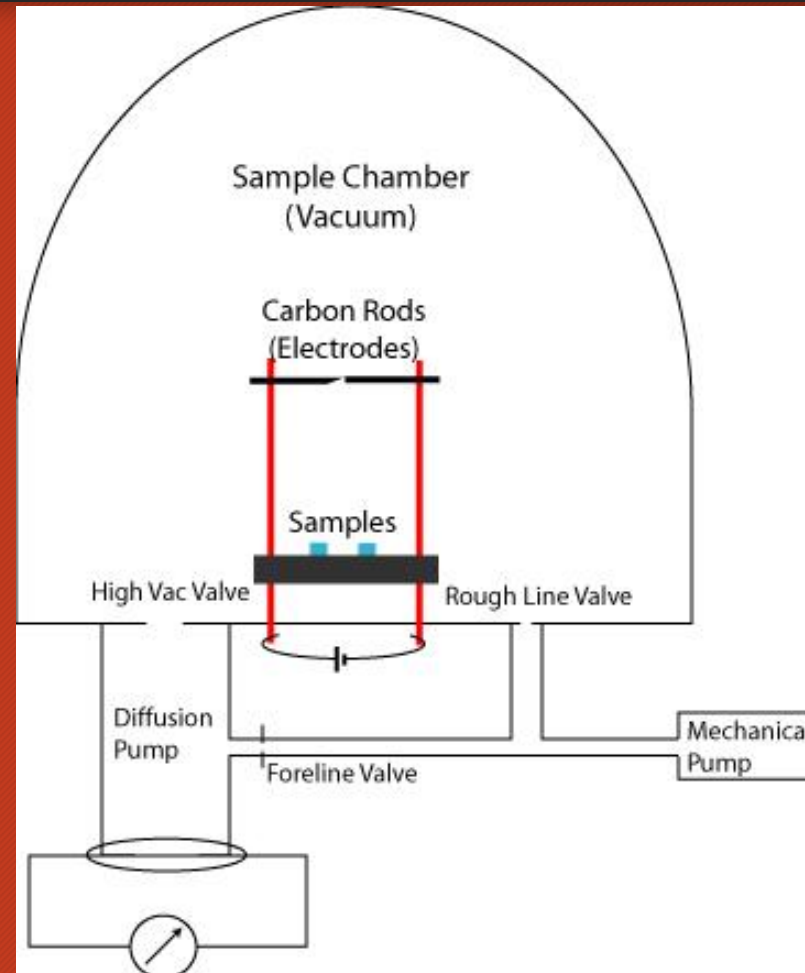
Qualitative analysis

Quantitative analysis



Carbon coating

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Thickness is monitored on a polished surface of brass, which is coated with the samples

Setting up the Electron Microprobe

Voltage, filament saturation and beam alignment

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- Accelerating voltage
 - Depends on *overvoltage* requirement,
e.g., *FeK α is not emitted with a 5 keV beam because $E_{c(K-shell)}=7.111$ keV, and $U < 1$.*
 - For a particular accelerating voltage, *overvoltage will be different for different elements. U should be about 2-10.*
- Filament saturation and beam alignment
 - *Saturation: filament current is adjusted to ensure saturation*
 - *Gun bias should be properly set to ensure optimum emission*
 - *Shift and tilt alignment: beam current is maximized*
 - *Wobble adjustment: image defocusing should be symmetrical above and below the optimum beam focusing plane. If not, position of the objective lens aperture is adjusted*
 - *Astigmatism correction: image is distorted if the spot is elliptical. Stigmator controls are used to remove distortion*

Setting up the Electron Microprobe

Spectrometer choice

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- Crystal/diffractor

E.g., $\text{FeK}\alpha$ ($\lambda_{\text{K}\alpha} = 0.1937 \text{ nm}$, $E_{\text{FeK}\alpha} = 6.4 \text{ keV}$) can be diffracted by TAP ($2d = 2.5757 \text{ nm}$), PET ($2d = 0.8742 \text{ nm}$) and LIF ($2d = 0.4027 \text{ nm}$).

For $n = 1$, equation $\lambda = 2d \sin \theta$, i.e., $\theta = \sin^{-1}\left(\frac{\lambda}{2d}\right)$, and for $R = 140 \text{ mm}$, equation $L = n\lambda \frac{140}{d}$ indicate:

$\theta = 4.3^\circ$ and $L = 191.2 \text{ mm}$ for TAP

$\theta = 12.8^\circ$ and $L = 62.0 \text{ mm}$ for PET

$\theta = 28.8^\circ$ and $L = 134.6 \text{ mm}$ for LIF

*Acceptable ranges for θ and L are 15-55° and 70-230 mm. Therefore, **LIF** is the correct choice.*

- Counter and window

*Xe has a better quantum efficiency for $\text{FeK}\alpha$. So, a **Xe counter** with a **Be window** is the right choice.*

- SCA settings

*Using **LIF/Xe counter** and an appropriate collection wire voltage, the $\text{CuK}\alpha$ ($E_{\text{CuK}\alpha} = 8.04 \text{ keV}$) pulse should be set at 5 V by performing **PHA**. Since $E_{\text{FeK}\alpha} = 0.8 \times E_{\text{CuK}\alpha}$ the $\text{FeK}\alpha$ pulse should be at $0.8 \times 5 = 4 \text{ V}$.*

- Detector slit

*For higher energy X-rays, smaller slits are recommended. The **300-550 μm** slit should be selected.*

Setting up the Electron Microprobe

Beam current, counting time and probe diameter

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- Beam current and counting time depend on concentration of the element of interest

Higher beam current increases count rate and longer counting time increases total counts (improves precision)

For N counts, the counting uncertainty is $\frac{1}{\sqrt{N}} \times 100 \%$. Counting is more precise as N increases. E.g.,

For 25 counts, the uncertainty is 20 %

For 100 counts, the uncertainty is 10 %

For 10,000 counts, the uncertainty is 1 %

- Probe diameter

Sometimes necessary to use a defocused beam (large spot size). E.g.,

Average composition of fine-grained material (spot size > grain size)

Hydrous, and Na or F containing glass: Na migrates away, F migrates toward the spot (spot size $\sim 10 \mu\text{m}$)

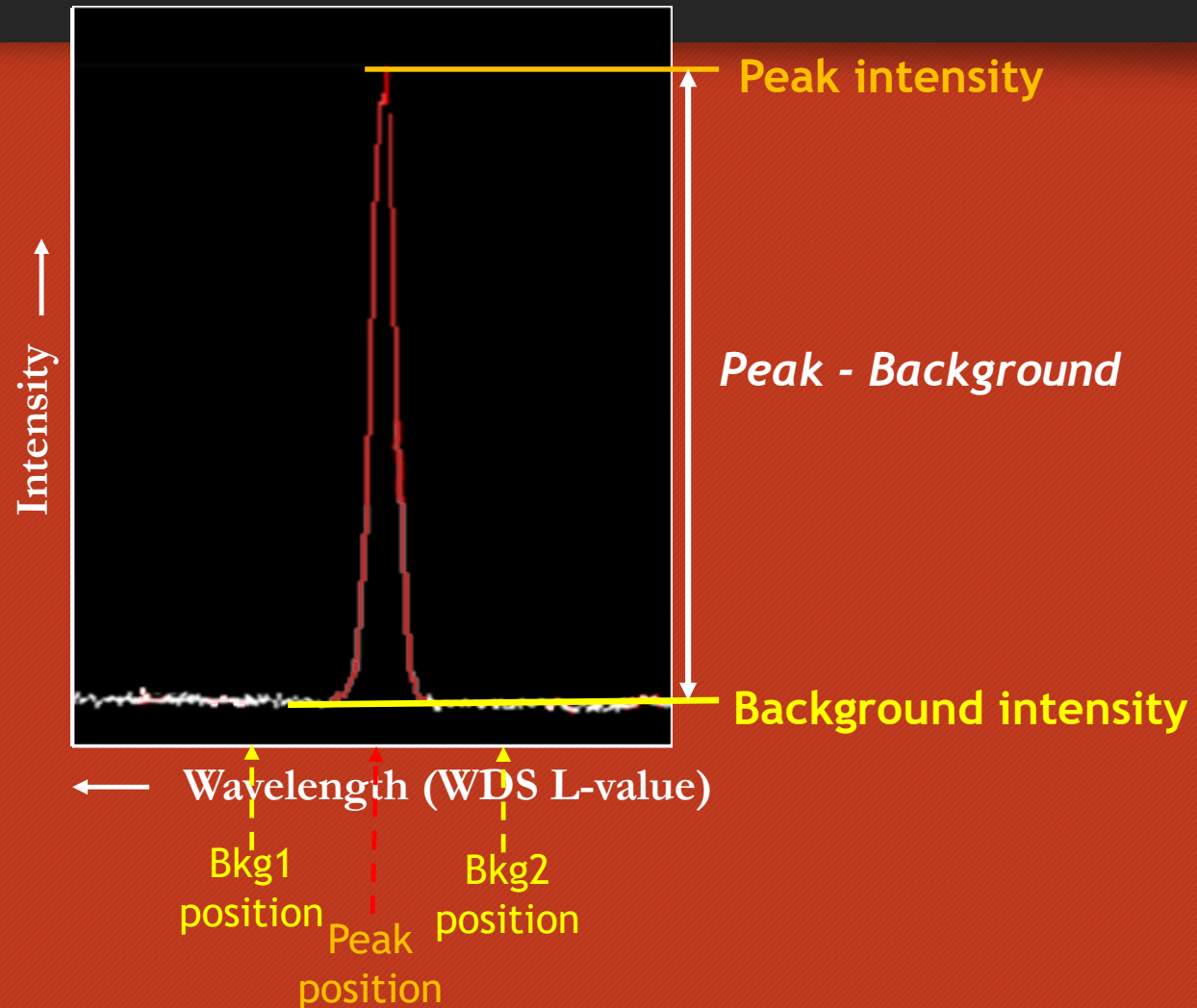
Standard x-ray intensity measurement (calibration)

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- *Calibration (standard intensity measurement) is performed on standards, a set of **homogenous**, natural or synthetic **compounds** with well **known composition***
- *A good calibration is essential for **accurate** analysis.
It eliminates **systematic errors***
- *After primary calibration, **secondary standards** (working standards) are analyzed to make sure the results are as expected*

X-ray intensity measurement

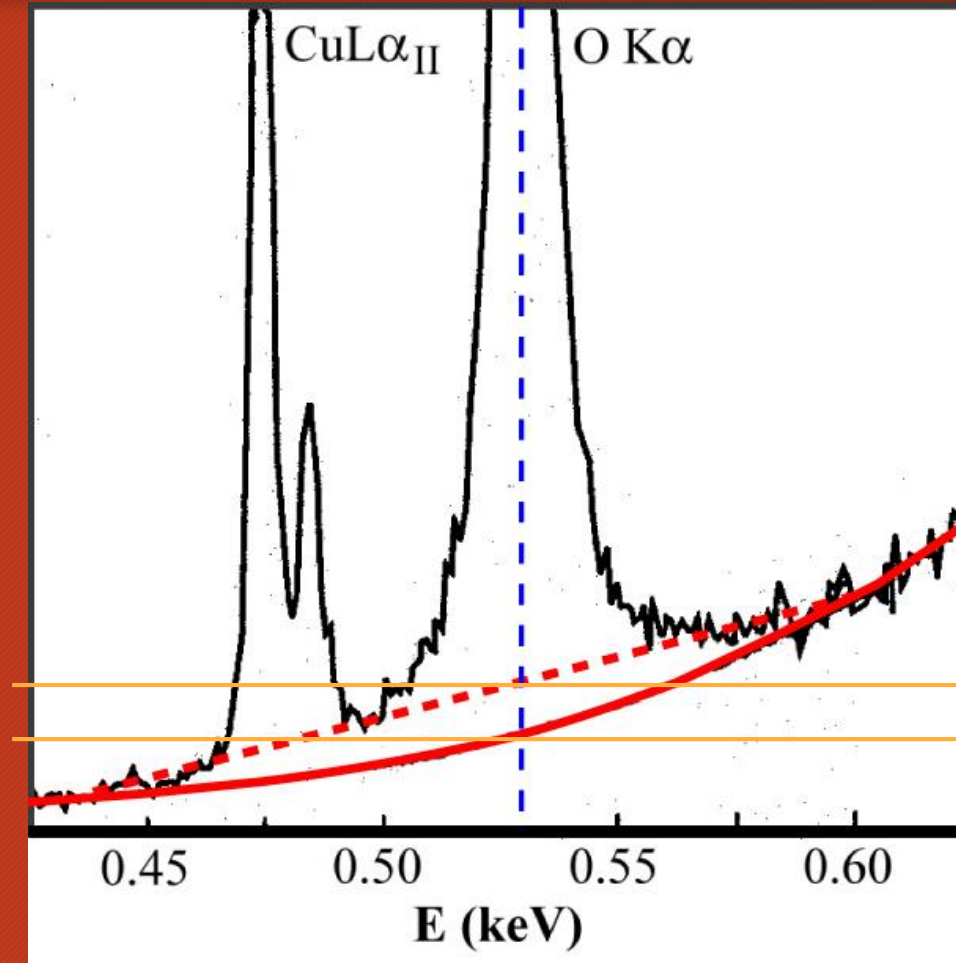
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Long counting times are used to achieve statistical precision

X-ray background measurement: special case

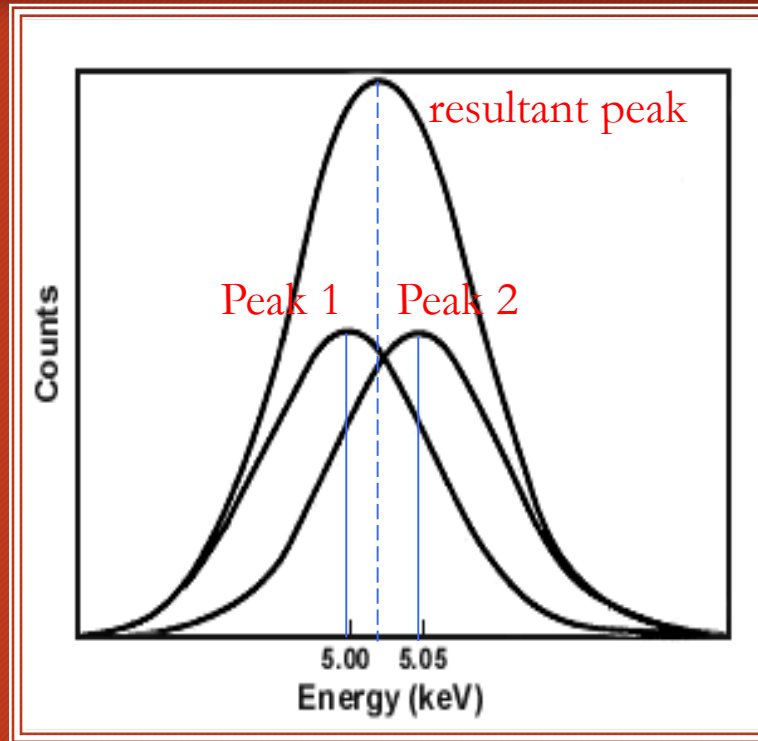
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incorrect
correct

Peak overlap in X-ray spectra

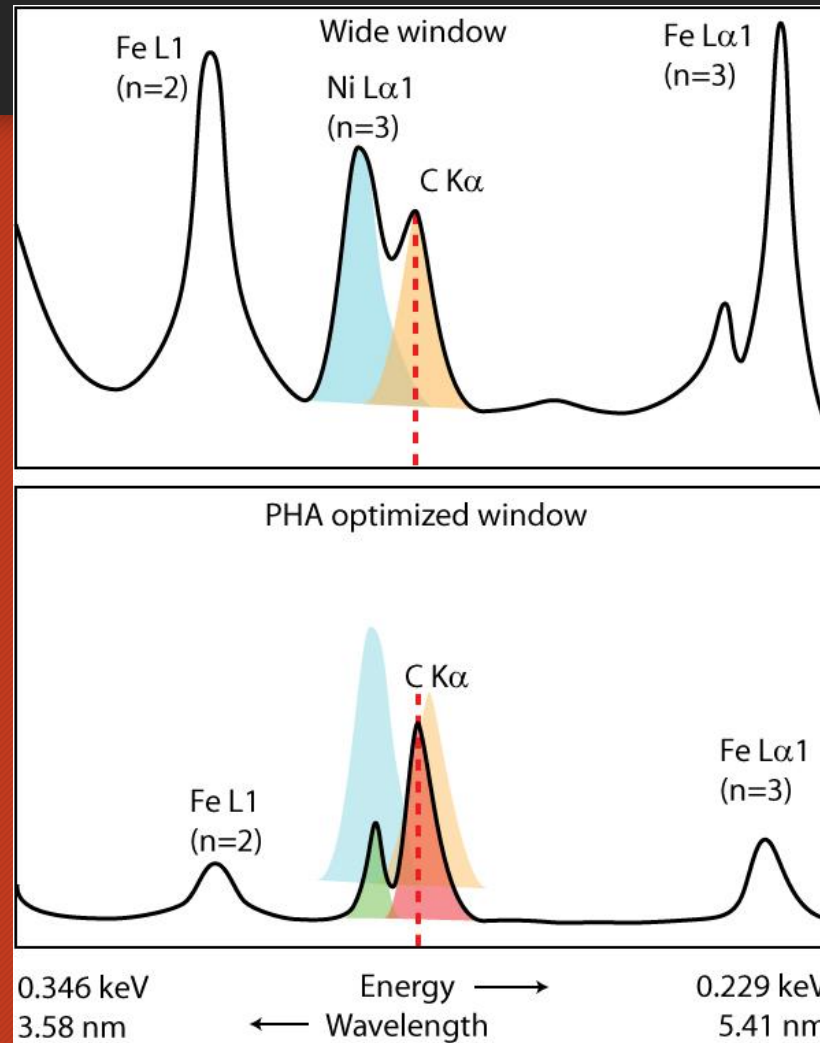
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Overlap between Peak 1 and Peak 2 results in a broad single peak

PHA reduces peak and background overlaps

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Wide open SCA voltage window

PHA optimized SCA voltage window

Spectrum of carbon steel

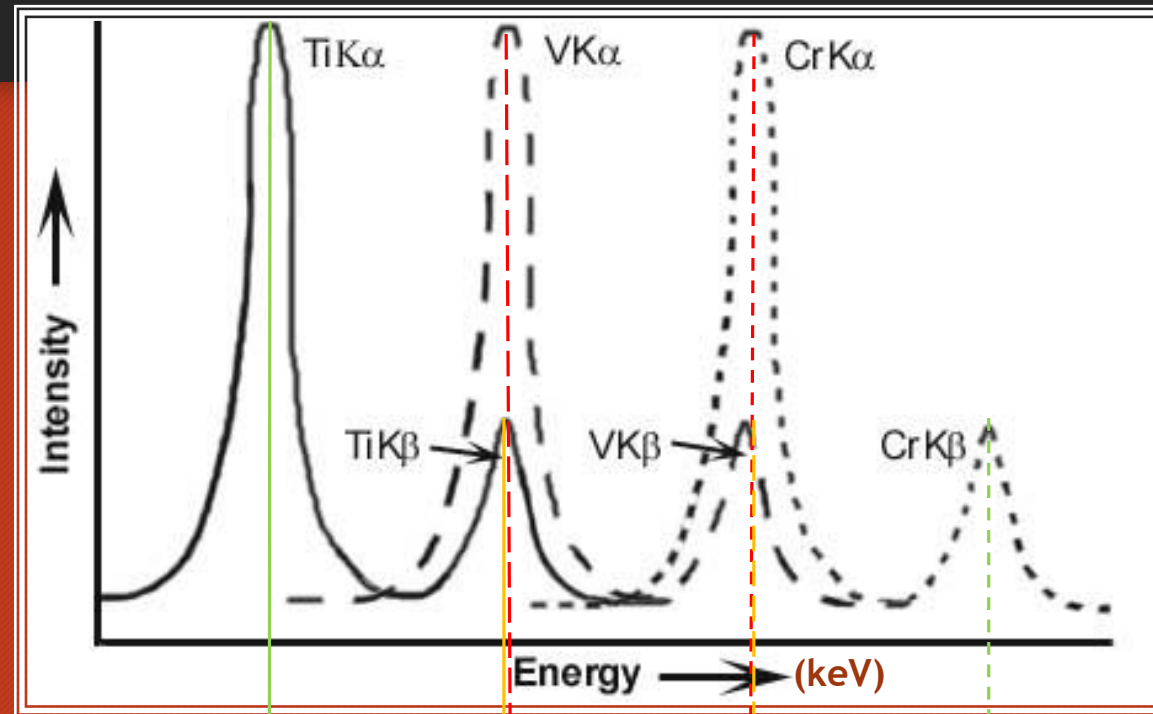
Peak overlap: $K\alpha$ and $K\beta$ of Ti, V and Cr

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Element	Atom No.	$K\alpha$	$K\alpha_1$ (°)	$K\alpha_2$	$K\beta$	$L\alpha$	$L\alpha_1$ (°)	$L\alpha_2$ (°)	$L\alpha_3$ (°)	$L\beta_{lab}$	$L\beta_{calc}$	M
Li	3	0.052			0.055							
Be	4	0.109			0.112							
B	5	0.183			0.192							
C	6	0.277			0.284							
N	7	0.392			0.400							
O	8	0.525			0.532							
F	9	0.677			0.687							
Ne	10	0.848			0.867							
Na	11	1.041			1.071							
Mg	12	1.253			1.303							
Al	13	1.486			1.560							
Si	14	1.739			1.840							
P	15	2.013	2.139(4)		2.143							
S	16	2.307	2.465(7)		2.470							
Cl	17	2.621	2.815(5)		2.819							
Ar	18	2.957	3.190(10)		3.202							
K	19	3.312	3.589(10)		3.607							
Ca	20	3.690	4.012(10)		4.037	0.341						
Sc	21	4.088	4.460(13)		4.488	0.395						
Ti	22	4.508	4.931(13)		4.964	0.452						
V	23	4.949	5.426(13)		5.463	0.511						
Cr	24	5.411	5.946(12)		5.988	0.573						
Mn	25	5.894	6.489(13)		6.536	0.637						
Fe	26	6.398	7.057(13)		7.110	0.705						
Co	27	6.924	7.648(13)		7.708	0.776						
Ni	28	7.471	8.263(13)		8.330	0.851						
Cu	29	8.040	8.904(13)		8.979	0.930						
Zn	30	8.630	9.570(13)		9.660	1.012						
Ga	31	9.241	10.262(14)		10.336	1.098						
Ge	32	9.874	10.978(14)		11.102	1.188						
As	33	10.530	11.722(15)		11.862	1.282						
Se	34	11.207	12.494(16)		12.652	1.419						
Br	35	11.907	13.286(16)		13.468	1.480						
Kr	36	12.631	14.107(16)		14.322	1.586						
Rb	37	13.373	14.956(16)		15.200	1.694						
Sr	38	14.140	15.830(16)		16.104	1.806						
Y	39	14.931	16.731(17)		17.035	1.922						
Zr	40	15.744	17.660(18)		17.996	2.042	2.124(45)					
Nb	41	16.581	18.729(8)		18.984	2.166	2.257(45)					
Mo	42	17.441	19.599(17)		20.001	2.293	2.394(45)					
Tc	43	18.325	20.608(16)		21.044	2.424	2.536(45)					
Ru	44	19.233	21.646(16)		22.116	2.558	2.683(45)					
Rh	45	20.165	22.712(16)		23.216	2.696	2.834(40)	3.001(25)				
Pd	46	21.121	23.806(17)		24.344	2.838	2.990(40)	3.171(25)				
Ag	47	22.101	24.928(17)		25.512	2.984	3.150(40)	3.347(25)				
Cd	48	23.106	26.081(18)		26.711	3.133	3.316(42)	3.528(25)				0.605
In	49	24.136	27.260(18)		27.937	3.286	3.487(75)	3.713(17)				
Sn	50	25.191	28.467(19)		29.190	3.443	3.662(75)	3.904(17)				0.691
Sb	51	26.271	29.396(19)		30.481	3.604	3.843(75)	4.100(17)				0.733
Te	52	27.468	30.974(19)		31.811	3.769	4.029(75)	4.301(17)				0.778
I	53	28.607	32.272(19)		33.167	3.937	4.220(75)	4.507(17)				
Xe	54	29.774	33.600(20)		34.590	4.109	4.420(50)	4.720(20)				
Cs	55	30.968	34.960(20)		35.987	4.286	4.619(50)	4.935(20)				
Ba	56	32.188	36.354(21)		37.452	4.465	4.827(50)	5.156(20)				0.972
La	57	33.436	37.771(21)		38.934	4.650	5.041(50)	5.383(20)				0.833
Ce	58	34.714	39.223(21)		40.453	4.839	5.261(50)	5.612(20)				0.883
Pr	59	36.020	40.771(21)		42.002	5.033	5.488(50)	5.849(20)				0.929
Nd	60	37.355			43.574	5.229	5.721(50)	6.088(20)				0.978
Pm	61	38.718			45.198	5.432	5.960(50)	6.338(20)				
Sm	62	40.111			46.849	5.635	6.204(50)	6.586(20)				1.081
Eu	63					5.845	6.455(50)	6.842(20)				1.131
Gd	64					6.056	6.712(50)	7.102(20)				1.185
Th	65					6.272	6.977(50)	7.365(20)				1.240
Dy	66					6.494	7.246(50)	7.634(20)				1.293
Ho	67					6.719	7.524(50)	7.910(20)				1.347
Er	68					6.947	7.809(50)	8.188(20)				1.405
Tm	69					7.179	8.100(50)	8.467(20)	9.424(5)			1.462
Yb	70					7.414	8.400(50)	8.757(20)	9.778(5)			1.521
Lu	71					7.654	8.708(50)	9.038(20)	10.142(6)			1.581
Hf	72					7.898	9.021(50)	9.346(20)	10.514(10)			1.644
Ta	73					8.145	9.342(50)	9.650(20)	10.893(10)			1.709
W	74					8.396	9.671(50)	9.960(20)	11.284(10)			1.774
Re	75					8.651	10.008(50)	10.274(20)	11.683(10)			1.842
Os	76					8.910	10.354(50)	10.597(20)	12.093(10)			1.914
Ir	77					9.174	10.706(50)	10.919(20)	12.510(10)			1.977
Pt	78					9.441	11.069(50)	11.249(20)	12.940(10)			2.048
Au	79					9.712	11.440(50)	11.583(20)	13.379(10)			2.121
Hg	80					9.987	11.821(50)	11.922(20)	13.828(10)			2.195
Tl	81					10.267	12.211(50)	12.270(20)	14.289(10)			2.267
Pb	82					10.550	12.612(50)	12.621(20)	14.762(10)			2.342
Bi	83					10.837	13.021(50)	12.978(20)	15.245(10)			2.419
Po	84					11.129	13.445(50)	13.338(20)	15.741(10)			
At	85					11.425	13.874(50)	14.065(10)	16.249(10)			
Rn	86					11.725	14.313(50)	14.509(10)	16.768(10)			
Fr	87					12.029	14.768(50)	14.448(20)	17.300(10)			
Ra	88					12.338	15.233(50)	14.839(20)	17.845(10)			
Ac	89					12.650	15.710(50)	15.929(10)	18.405(10)			
Th	90					12.967	16.199(50)	15.621(20)	18.979(10)			2.991
Pa	91					13.288	16.699(50)	16.022(20)	19.565(10)			3.077
U	92					13.612	17.217(50)	16.425(20)	20.164(10)			3.165

Peak overlap correction for Ti-V-Cr

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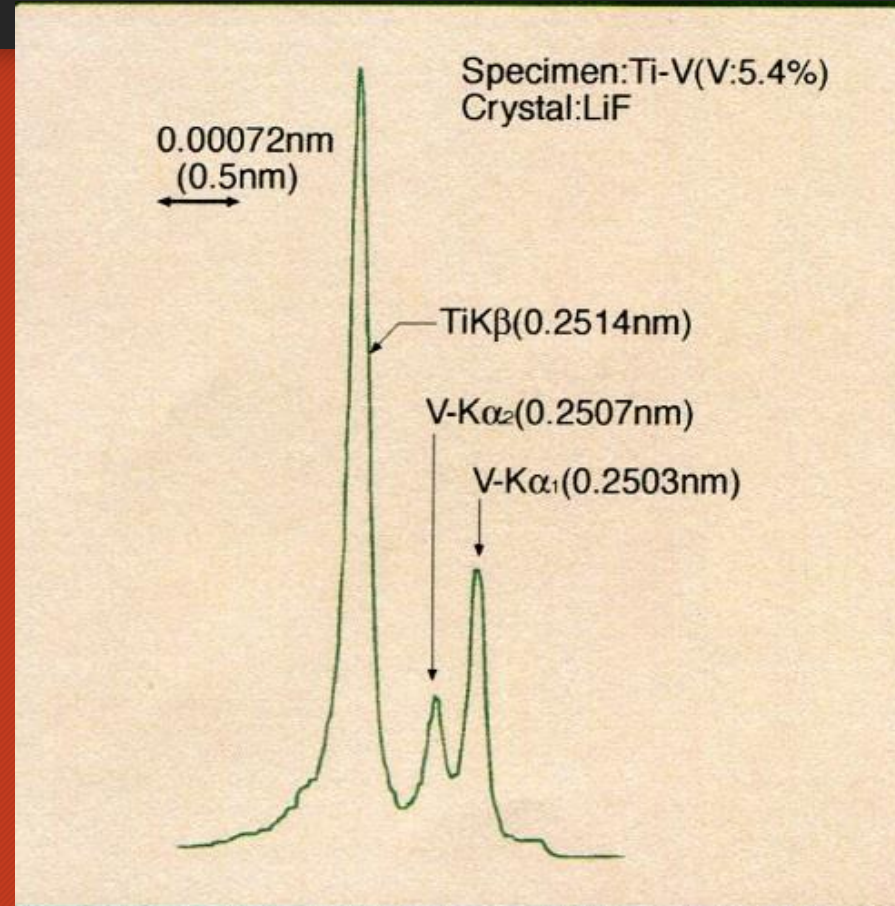


$$I_{VK\alpha}^{\text{corr}} = I_{VK\alpha}^{\text{meas}} - \frac{I_{TiK\alpha}^{\text{meas}}}{I_{TiK\alpha}^{\text{std}}} I_{VK\alpha}^{\text{std}}$$

$$I_{CrK\alpha}^{\text{corr}} = I_{CrK\alpha}^{\text{meas}} - \frac{I_{VK\alpha}^{\text{corr}}}{I_{VK\alpha}^{\text{std}}} I_{CrK\alpha}^{\text{std}}$$

Peak resolution with LIF

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LIF is able to resolve the
TiK β , VK α_1 and VK α_2 peaks

XCE type spectrometer with Xe counter

EPMA Quantitative analysis

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X-ray intensity is proportional to the concentration, $C \propto I$

$$\frac{C_i}{C_{(i)}} \propto \frac{I_i}{I_{(i)}}$$

C_i , I_i : concentration and intensity in sample

$C_{(i)}$, $I_{(i)}$: concentration and intensity in standard

$$\frac{I_i}{I_{(i)}} = k_i \text{ (k - ratio)}$$

$$\frac{C_i}{C_{(i)}} = k_i \cdot [\text{ZAF}]_i$$

ZAF Matrix corrections:

Z: Atomic Number correction

A: Absorption correction

F: Fluorescence correction

Typical quantitative analysis output

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		k-ratio	Element Wt%		Oxide Wt%		Atomic proportion	
Element		k-Ratio	El-Wt%	MDLeI%	Ox-Wt%	MDLox%	At-Prop	Error%
SiO ₂	Ka	0.9119	17.30	0.03	37.01	0.05	2.960	0.68%
TiO ₂	Ka	0.0021	0.13	0.05	0.22	0.09	0.013	20.28%
Al ₂ O ₃	Ka	0.5200	11.46	0.03	21.66	0.05	2.042	0.86%
Cr ₂ O ₃	Ka	0.0000	0.00	0.06	0.00	0.08	0.000	99.00%
FeO	Ka	1.0431	21.43	0.07	27.57	0.09	1.844	1.58%
MnO	Ka	0.0809	2.89	0.08	3.73	0.11	0.253	4.29%
MgO	Ka	0.0781	1.36	0.02	2.26	0.04	0.269	2.93%
CaO	Ka	0.3565	5.20	0.04	7.28	0.05	0.624	1.82%
Na ₂ O	Ka	0.0011	0.01	0.04	0.02	0.05	0.003	99.00%
O			39.95				12.000	
Total:			99.75		99.75	Cation:	8.007	

Minimum detection limit (El-Wt%) Minimum detection limit (Ox-Wt%) Cation Sum based on a certain #O Uncertainty

Typical quantitative analysis output

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Element	Oxide Wt%	Atomic proportion
SiO ₂	37.01	2.960
TiO ₂	0.22	0.013
Al ₂ O ₃	21.66	2.042
Cr ₂ O ₃	0.00	0.000
FeO	27.57	1.844
MnO	3.73	0.253
MgO	2.26	0.269
CaO	7.28	0.624
Na ₂ O	0.02	0.003
O		12.000
Total:	99.75	8.007

- A typical mineral analysis reports Oxide wt% and Atomic proportions
- The wt% total and cation sum give us an idea of the quality of the analysis
- Atomic proportions give us the formula: $\text{Mg}_{0.27}\text{Fe}_{1.84}\text{Mn}_{0.25}\text{Ca}_{0.62}\text{Al}_{2.04}\text{Si}_{2.96}\text{O}_{12}$ (garnet)